



SHEET 1 OF 1

**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

**INFORMATION  
DISCLOSURE  
CITATION**  
PTO-1449

JUN 04 2004  
U.S. PATENT & TRADEMARK OFFICE  
ST. LOUIS, MO

Customer Number  
**26615**

ATTORNEY'S DKT No.  
**H1105D**

APPLICATION NO.  
**10/602,061**

APPLICANT(S)  
**Shibly S. AHMED et al.**

FILING DATE  
**June 24, 2003**

GROUP  
**Unassigned**

*2812*

**U.S. PATENT DOCUMENTS**

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<i>RP</i>	5,563,082	10-08-96	Mukai	437	41	12-23-94
<i>RP</i>	6,413,802 B1	07-02-02	Hu et al.	438	151	10-23-00

**FOREIGN PATENT DOCUMENTS**

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

<i>RP</i>	Leland Chang et al.: "Gate Length Scaling and Threshold Voltage Control of Double-Gate MOSFETs," IEDM, December 10, 2000, pages 719-722.

EXAMINER	<i>Rm Pompey</i>	DATE CONSIDERED	<i>4-26-05</i>
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